D DACKAOF

14 🛛 O₅

13 🛛 O₆

12 O7

11

LE

- Function and Pinout Compatible With FCT and F Logic
- Reduced V_{OH} (Typically = 3.3 V) Versions of Equivalent FCT Functions
- Edge-Rate Control Circuitry for Significantly Improved Noise Characteristics
- I_{off} Supports Partial-Power-Down Mode Operation
- ESD Protection Exceeds JESD 22
 2000-V Human-Body Model (A114-A)
 - 200-V Machine Model (A115-A)
 - 1000-V Charged-Device Model (C101)
- Matched Rise and Fall Times
- Fully Compatible With TTL Input and Output Logic Levels
- 3-State Outputs
- CY54FCT573T
 - 32-mA Output Sink Current
 - 12-mA Output Source Current
- CY74FCT573T
 - 64-mA Output Sink Current
 - 32-mA Output Source Current

description

The 'FCT573T devices consist of eight latches with 3-state outputs for bus-organized applications. When the latch-enable (LE) input is high, the flip-flops appear transparent to the data. Data that meets the required setup times are latched when LE transitions from high to low. Data appears on the bus when the output-enable (\overline{OE}) input is low. When \overline{OE} is high, the bus output is in the high-impedance state. In this mode, data can be entered into the latches. The 'FCT573T devices are identical to the 'FCT373T devices, except for the flow-through pinout of the 'FCT573T, which simplifies board design.

These devices are fully specified for partial-power-down applications using I_{off}. The I_{off} circuitry disables the outputs, preventing damaging current backflow through the device when it is powered down.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



Copyright © 2001, Texas Instruments Incorporated On products compliant to MIL-PRF-38535, all parameters are tested unless otherwise noted. On all other products, production processing does not necessarily include testing of all parameters.

CY54FC1573T D PACKAGE CY74FCT573T P, Q, OR SO PACKAGE (TOP VIEW)										
OE [1	20	$ \begin{array}{c} V_{CC}\\O_0\\O_1\\O_2\\O_3\\O_4\end{array} $							
D ₀ [2	19								
D ₁ [3	18								
D ₂ [4	17								
D ₃ [5	16								
D ₄ [6	15								

D₅ 7

D₆ [8

D₇ 9

GND 10

CY54FCT573T, CY74FCT573T 8-BIT LATCHES WITH 3-STATE OUTPUTS SCCS068 - OCTOBER 2001

TA	PAC	KAGE [†]	SPEED (ns)	ORDERABLE PART NUMBER	TOP-SIDE MARKING						
	QSOP – Q	P – Q Tape and reel 4.7 CY74FCT573CTQCT		FCT573C							
	SOIC – SO	Tube	4.7	CY74FCT573CTSOC	FCT573C						
	5010 - 50	Tape and reel 4.7 CY74FCT573CTSOCT		FC1573C							
	DIP – P	Tube	5.2	CY74FCT573ATPC	CY74FCT573ATPC						
-40°C to 85°C	QSOP – Q	Tape and reel	5.2	CY74FCT573ATQCT	FCT573A						
-40 C 10 85 C	0010 00	SOIC – SO		5.2	CY74FCT573ATSOC	FCT573A					
	3010 - 30	Tape and reel	5.2	CY74FCT573ATSOCT	FC1575A						
	QSOP – Q	Tape and reel	8	CY74FCT573TQCT	FCT573						
	SOIC – SO	Tube	8	CY74FCT573TSOC	FCT573						
	3010 - 30	Tape and reel	8	CY74FCT573TSOCT	FU1073						
–55°C to 125°C	CDIP – D	Tube	8.5	CY54FCT573ATLMB							

ORDERING INFORMATION

[†] Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.

FUNCTION TABLE

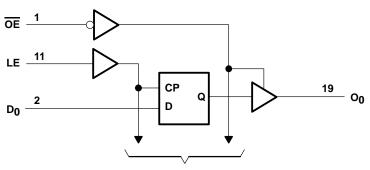
	INPUTS		OUTPUT
OE	LE	D	0
L	Н	Н	Н
L	Н	L	L
L	L	Х	Q ₀
н	Х	Х	Z

H = High logic level, L = Low logic level,

X = Don't care, Z = High-impedance state, Q_n = Previous state of flip flops (Q_{n-1})

 $\alpha_n = \text{Previous state of hip hops} (\alpha_{n-1})$

logic diagram (positive logic)



To Seven Other Channels



CY54FCT573T, CY74FCT573T **8-BIT LATCHES** WITH 3-STATE OUTPUTS

SCCS068 - OCTOBER 2001

absolute maximum rating over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range to ground potential		0.5	V to 7 V
DC input voltage range		0.5	V to 7 V
DC output voltage range		0.5	V to 7 V $$
DC output current (maximum sink current/pin)			120 mA
Package thermal impedance, θ_{JA} (see Note 1):	P package		69°C/W
	Q package		68°C/W
	SO package		58°C/W
Ambient temperature range with power applied,	, T _A	–65°C ⁻	to 135°C
Storage temperature range, T _{stg}		–65°C	to 150°C

† Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The package thermal impedance is calculated in accordance with JESD 51-7.

recommended operating conditions (see Note 2)

		CY54FCT573			CY	4FCT57	'3T	UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
VCC	Supply voltage	4.5	5	5.5	4.75	5	5.25	V
VIH	High-level input voltage	2			2			V
VIL	Low-level input voltage			0.8			0.8	V
ЮН	High-level output current			-12			-32	mA
IOL	Low-level output current			32			64	mA
Т _А	Operating free-air temperature	-55		125	-40		85	°C

NOTE 2: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation.



CY54FCT573T, CY74FCT573T **8-BIT LATCHES** WITH 3-STATE OUTPUTS

SCCS068 - OCTOBER 2001

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DAD AMETER	TERT CONDITIONS	CY	54FCT57	73T	CY	74FCT57	′3T	UNIT				
PARAMETER	TEST CONDITIONS	MIN	түр†	MAX	MIN	түр†	MAX	UNIT				
Maria	V _{CC} = 4.5 V, I _{IN} = -18 mA		-0.7	-1.2				v				
VIK	$V_{CC} = 4.75 \text{ V}, I_{IN} = -18 \text{ mA}$					-0.7	-1.2	v				
	$V_{CC} = 4.5 \text{ V}, \qquad I_{OH} = -12 \text{ mA}$	2.4	3.3									
Vон	$I_{OH} = -32 \text{ mA}$				2			V				
	$V_{CC} = 4.75 \text{ V}$ $I_{OH} = -15 \text{ mA}$				2.4	3.3						
Ve	$V_{CC} = 4.5 \text{ V}, \qquad I_{OL} = 32 \text{ mA}$		0.3	0.55				v				
VOL	$V_{CC} = 4.75 \text{ V}, I_{OL} = 64 \text{ mA}$					0.3	0.55	v				
V _{hys}	All inputs		0.2			0.2		V				
1.	$V_{CC} = 5.5 \text{ V}, \qquad V_{IN} = V_{CC}$			5				μA				
łı	$V_{CC} = 5.25 \text{ V}, V_{IN} = V_{CC}$						5	μA				
I	$V_{CC} = 5.5 \text{ V}, \qquad V_{IN} = 2.7 \text{ V}$			±1				μA				
ŀІН	$V_{CC} = 5.25 \text{ V}, V_{IN} = 2.7 \text{ V}$						±1	μА				
1	$V_{CC} = 5.5 \text{ V}, \qquad V_{IN} = 0.5 \text{ V}$			±1				μA				
ΙL	$V_{CC} = 5.25 \text{ V}, V_{IN} = 0.5 \text{ V}$						±1	μA				
	V _{CC} = 5.5 V, V _{OUT} = 2.7 V			10								
IOZH	V _{CC} = 5.25 V, V _{OUT} = 2.7 V						10	μA				
	V _{CC} = 5.5 V, V _{OUT} = 0.5 V			-10								
IOZL	V _{CC} = 5.25 V, V _{OUT} = 0.5 V						-10	μA				
le et	V _{CC} = 5.5 V, V _{OUT} = 0 V	-60	-120	-225				~				
IOS‡	V _{CC} = 5.25 V, V _{OUT} = 0 V				-60	-120	-225	mA				
loff	V _{CC} = 0 V, V _{OUT} = 4.5 V			±1			±1	μA				
	$V_{CC} = 5.5 \text{ V}, \qquad V_{IN} \le 0.2 \text{ V}, \qquad \qquad V_{IN} \ge V_{CC} - 0.2 \text{ V}.$	2 V	0.1	0.2				m 4				
ICC	$V_{CC} = 5.25 \text{ V}, \qquad V_{IN} \le 0.2 \text{ V}, \qquad \qquad V_{IN} \ge V_{CC} - 0.2 \text{ V}.$	2 V				0.1	0.2	mA				
	$V_{CC} = 5.5 \text{ V}, \text{ V}_{IN} = 3.4 \text{ V}$ $\text{$\%$}, \text{$f_1 = 0$, Outputs open}$		0.5	2				س ۸				
⊅ICC	V_{CC} = 5.25 V, V_{IN} = 3.4 V§, f ₁ = 0, Outputs open					0.5	2	mA				
۹	V_{CC} = 5.5 V, Outputs open, One input switching at 50% duty cycle, \overline{OE} = GND, $V_{IN} \le 0.2$ V or $V_{IN} \ge V_{CC} - 0.2$ V		0.06	0.12				mA				
ICCD	$V_{CC} = 5.25$ V, Outputs open, One input switching at 50% duty cycle, $\overline{OE} = GND$, $V_{IN} \le 0.2$ V or $V_{IN} \ge V_{CC} - 0.2$ V					0.06	0.12	МН				

[†] Typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

[‡] Not more than one output should be shorted at a time. Duration of short should not exceed one second. The use of high-speed test apparatus and/or sample-and-hold techniques are preferable to minimize internal chip heating and more accurately reflect operational values. Otherwise, prolonged shorting of a high output can raise the chip temperature well above normal and cause invalid readings in other parametric tests. In any sequence of parameter tests, IOS tests should be performed last.

§ Per TTL-driven input (V_{IN} = 3.4 V); all other inputs at V_{CC} or GND

¶ This parameter is derived for use in total power-supply calculations.



CY54FCT573T, CY74FCT573T 8-BIT LATCHES WITH 3-STATE OUTPUTS

SCCS068 - OCTOBER 2001

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted) (continued)

DADAMETER		TEST CONDITION	c	CY	54FCT57	73T	CY	74FCT57	73T	UNIT
PARAMETER		TEST CONDITION	5	MIN	түр†	MAX	MIN	түр†	MAX	UNIT
		One bit switching at f ₁ = 10 MHz	$\begin{array}{l} V_{IN} \leq 0.2 \ V \ or \\ V_{IN} \geq V_{CC} - 0.2 \ V \end{array}$		0.7	1.4				
	V _{CC} = 5.5 V, Outputs open,	at 50% duty cycle	$V_{IN} = 3.4 \text{ V or GND}$		1	2.4				
	$\overline{OE} = GND,$ LE = V _{CC}	Eight bits switching at $f_1 = 2.5$ MHz	$V_{IN} \leq 0.2 \text{ V or} \\ V_{IN} \geq V_{CC} - 0.2 \text{ V}$		1.3	2.6				
IC#		at 50% duty cycle	$V_{IN} = 3.4 \text{ V or GND}$		3.3	10.6ll				mA
'C"	Voo – 5 25 V	One bit switching at f ₁ = 10 MHz	$\begin{array}{l} V_{IN} \leq 0.2 \ V \ or \\ V_{IN} \geq V_{CC} - 0.2 \ V \end{array} \end{array} \label{eq:VIN}$					0.7	1.4	ША
	V _{CC} = 5.25 V, Outputs open,	at 50% duty cycle	$V_{IN} = 3.4 \text{ V or GND}$					1	2.4	
	$\overline{OE} = GND,$ LE = V _{CC}	Eight bits switching at f ₁ = 2.5 MHz	$\begin{array}{l} V_{IN} \leq 0.2 \ V \ or \\ V_{IN} \geq V_{CC} - 0.2 \ V \end{array} \end{array} \label{eq:VIN}$					1.3	2.6	
		at 50% duty cycle	$V_{IN} = 3.4 \text{ V or GND}$					3.3	10.6ll	
Ci					6	10		6	10	pF
Co					8	12		8	12	pF

[†] Typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}C$.

[#] IC = ICC + Δ ICC × D_H × N_T + I_{CCD} (f₀/2 + f₁ × N₁)

Where:

= Total supply current IC

ICC = Power-supply current with CMOS input levels

 ΔI_{CC} = Power-supply current for a TTL high input (VIN = 3.4 V)

 D_H = Duty cycle for TTL inputs high NT = Number of TTL inputs at D_H

I_{CCD} = Dynamic current caused by an input transition pair (HLH or LHL)

= Clock frequency for registered devices, otherwise zero fo

= Input signal frequency f1

N₁ = Number of inputs changing at f1

All currents are in milliamperes and all frequencies are in megahertz.

|| Values for these conditions are examples of the I_{CC} formula.

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figure 1)

		CY54FC	T573T	CY54FCT	573AT	UNIT
		MIN	MAX	MIN	MAX	
tw	Pulse duration, LE high	6		6		ns
t _{su}	Setup time, data before LE [↑]	2		2		ns
th	Hold time, data after LE↑	1.5		1.5		ns

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figure 1)

		CY74FCT573T		CY74FCT	573AT	CY74FCT	UNIT	
		MIN	MAX	MIN	MAX	MIN	MAX	UNIT
tw	Pulse duration, LE high	6		5		5		ns
t _{su}	Setup time, data before LE↑	2		2		2		ns
th	Hold time, data after LE↑	1.5		1.5		1.5		ns



CY54FCT573T, CY74FCT573T 8-BIT LATCHES WITH 3-STATE OUTPUTS SCCS068 - OCTOBER 2001

switching characteristics over operating free-air temperature range (see Figure 1)

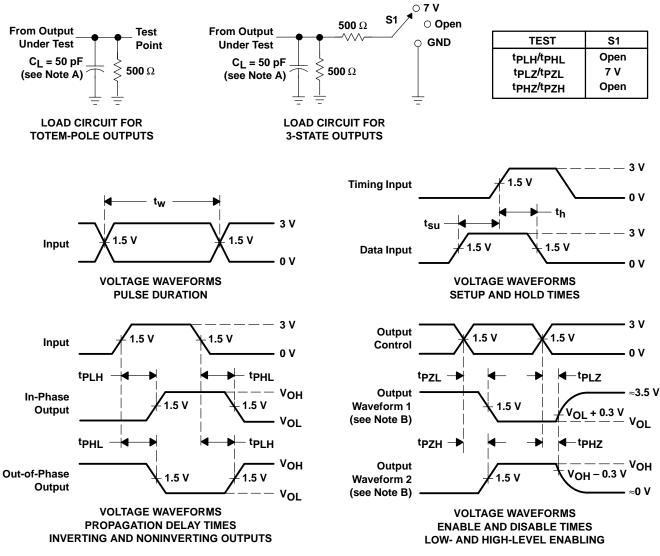
PARAMETER	FROM	то	CY54FCT	573AT	UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	MAX	UNIT
^t PLH	D	0	1.5	5.6	ns
^t PHL	J	0	1.5	5.6	115
^t PLH	LE	0	2	9.8	ns
^t PHL	EL .	0	2	9.8	115
^t PZH	OE	0	1.5	7.5	ns
^t PZL	ÖE	0	1.5	7.5	115
^t PHZ	OE	0	1.5	6.5	ns
^t PLZ	UE UE	5	1.5	6.5	115

switching characteristics over operating free-air temperature range (see Figure 1)

DADAMETER	PARAMETER FROM		CY74FC	CY74FCT573T		CY74FCT573AT		CY74FCT573CT	
PARAMETER	(INPUT)	(OUTPUT)	MIN	MAX	MIN	MAX	MIN	MAX	UNIT
^t PLH	D	0	1.5	8	1.5	5.2	1.5	4.7	ns
^t PHL	D	0	1.5	8	1.5	5.2	1.5	4.7	115
^t PLH	LE	0	2	13	2	8.5	2	5.5	
^t PHL	LL	0	2	13	2	8.5	2	5.5	ns
^t PZH	OE	0	1.5	12	1.5	6.5	1.5	5.5	
^t PZL	OE	0	1.5	12	1.5	6.5	1.5	5.5	ns
^t PHZ	OE	0	1.5	7.5	1.5	5.5	1.5	5	ns
^t PLZ	UE	0	1.5	7.5	1.5	5.5	1.5	5	115



CY54FCT573T, CY74FCT573T 8-BIT LATCHES WITH 3-STATE OUTPUTS SCCS068 - OCTOBER 2001



PARAMETER MEASUREMENT INFORMATION

NOTES: A. C_L includes probe and jig capacitance.

B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.

C. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms





www.ti.com

5-Sep-2011

PACKAGING INFORMATION

Orderable Device	Status ⁽¹⁾	Package Type	Package Drawing	Pins	Package Qty	Eco Plan ⁽²⁾	Lead/ Ball Finish	MSL Peak Temp ⁽³⁾	Samples (Requires Login)
5962-9223801MRA	ACTIVE	CDIP	J	20	1	TBD	A42	N / A for Pkg Type	
5962-9223802M2A	ACTIVE	LCCC	FK	20	1	TBD	Call TI	Call TI	
CY54FCT573ATLMB	ACTIVE	LCCC	FK	20	1	TBD	POST-PLATE	N / A for Pkg Type	
CY74FCT573ATPC	ACTIVE	PDIP	Ν	20	20	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	
CY74FCT573ATPCE4	ACTIVE	PDIP	Ν	20	20	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	
CY74FCT573ATQCT	ACTIVE	SSOP/QSOP	DBQ	20	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	
CY74FCT573ATQCTE4	ACTIVE	SSOP/QSOP	DBQ	20	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	
CY74FCT573ATQCTG4	ACTIVE	SSOP/QSOP	DBQ	20	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	
CY74FCT573ATSOC	ACTIVE	SOIC	DW	20	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
CY74FCT573ATSOCE4	ACTIVE	SOIC	DW	20	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
CY74FCT573ATSOCG4	ACTIVE	SOIC	DW	20	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
CY74FCT573ATSOCT	ACTIVE	SOIC	DW	20	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
CY74FCT573ATSOCTE4	ACTIVE	SOIC	DW	20	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
CY74FCT573ATSOCTG4	ACTIVE	SOIC	DW	20	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
CY74FCT573CTQCT	ACTIVE	SSOP/QSOP	DBQ	20	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	
CY74FCT573CTQCTE4	ACTIVE	SSOP/QSOP	DBQ	20	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	
CY74FCT573CTQCTG4	ACTIVE	SSOP/QSOP	DBQ	20	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	
CY74FCT573CTSOC	ACTIVE	SOIC	DW	20	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
CY74FCT573CTSOCG4	ACTIVE	SOIC	DW	20	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	



5-Sep-2011

Orderable Device	Status ⁽¹⁾	Package Type	Package Drawing	Pins	Package Qty	Eco Plan ⁽²⁾	Lead/ Ball Finish	MSL Peak Temp ⁽³⁾	Samples (Requires Login)
CY74FCT573TQCT	ACTIVE	SSOP/QSOP	DBQ	20	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	
CY74FCT573TQCTE4	ACTIVE	SSOP/QSOP	DBQ	20	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	
CY74FCT573TQCTG4	ACTIVE	SSOP/QSOP	DBQ	20	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	
CY74FCT573TSOC	ACTIVE	SOIC	DW	20	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
CY74FCT573TSOCE4	ACTIVE	SOIC	DW	20	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
CY74FCT573TSOCG4	ACTIVE	SOIC	DW	20	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
CY74FCT573TSOCT	ACTIVE	SOIC	DW	20	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
CY74FCT573TSOCTE4	ACTIVE	SOIC	DW	20	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
CY74FCT573TSOCTG4	ACTIVE	SOIC	DW	20	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

⁽²⁾ Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

⁽³⁾ MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.



www.ti.com

5-Sep-2011

Important Information and Disclaimer:The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

PACKAGE MATERIALS INFORMATION

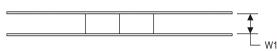
www.ti.com

TAPE AND REEL INFORMATION

REEL DIMENSIONS

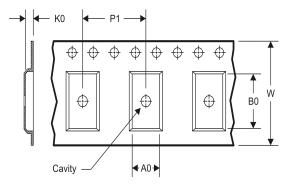
TEXAS INSTRUMENTS





TAPE AND REEL INFORMATION

TAPE DIMENSIONS



A0	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

*All dimensions are nominal												
Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CY74FCT573ATQCT	SSOP/ QSOP	DBQ	20	2500	330.0	16.4	6.5	9.0	2.1	8.0	16.0	Q1
CY74FCT573ATSOCT	SOIC	DW	20	2000	330.0	24.4	10.8	13.0	2.7	12.0	24.0	Q1
CY74FCT573CTQCT	SSOP/ QSOP	DBQ	20	2500	330.0	16.4	6.5	9.0	2.1	8.0	16.0	Q1
CY74FCT573TQCT	SSOP/ QSOP	DBQ	20	2500	330.0	16.4	6.5	9.0	2.1	8.0	16.0	Q1
CY74FCT573TSOCT	SOIC	DW	20	2000	330.0	24.4	10.8	13.0	2.7	12.0	24.0	Q1

TEXAS INSTRUMENTS

www.ti.com

PACKAGE MATERIALS INFORMATION

14-Jul-2012



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CY74FCT573ATQCT	SSOP/QSOP	DBQ	20	2500	367.0	367.0	38.0
CY74FCT573ATSOCT	SOIC	DW	20	2000	367.0	367.0	45.0
CY74FCT573CTQCT	SSOP/QSOP	DBQ	20	2500	367.0	367.0	38.0
CY74FCT573TQCT	SSOP/QSOP	DBQ	20	2500	367.0	367.0	38.0
CY74FCT573TSOCT	SOIC	DW	20	2000	367.0	367.0	45.0

IMPORTANT NOTICE

Texas Instruments Incorporated and its subsidiaries (TI) reserve the right to make corrections, enhancements, improvements and other changes to its semiconductor products and services per JESD46C and to discontinue any product or service per JESD48B. Buyers should obtain the latest relevant information before placing orders and should verify that such information is current and complete. All semiconductor products (also referred to herein as "components") are sold subject to TI's terms and conditions of sale supplied at the time of order acknowledgment.

TI warrants performance of its components to the specifications applicable at the time of sale, in accordance with the warranty in TI's terms and conditions of sale of semiconductor products. Testing and other quality control techniques are used to the extent TI deems necessary to support this warranty. Except where mandated by applicable law, testing of all parameters of each component is not necessarily performed.

TI assumes no liability for applications assistance or the design of Buyers' products. Buyers are responsible for their products and applications using TI components. To minimize the risks associated with Buyers' products and applications, Buyers should provide adequate design and operating safeguards.

TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right relating to any combination, machine, or process in which TI components or services are used. Information published by TI regarding third-party products or services does not constitute a license to use such products or services or a warranty or endorsement thereof. Use of such information may require a license from a third party under the patents or other intellectual property of the third party, or a license from TI under the patents or other intellectual property of TI.

Reproduction of significant portions of TI information in TI data books or data sheets is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations, and notices. TI is not responsible or liable for such altered documentation. Information of third parties may be subject to additional restrictions.

Resale of TI components or services with statements different from or beyond the parameters stated by TI for that component or service voids all express and any implied warranties for the associated TI component or service and is an unfair and deceptive business practice. TI is not responsible or liable for any such statements.

Buyer acknowledges and agrees that it is solely responsible for compliance with all legal, regulatory and safety-related requirements concerning its products, and any use of TI components in its applications, notwithstanding any applications-related information or support that may be provided by TI. Buyer represents and agrees that it has all the necessary expertise to create and implement safeguards which anticipate dangerous consequences of failures, monitor failures and their consequences, lessen the likelihood of failures that might cause harm and take appropriate remedial actions. Buyer will fully indemnify TI and its representatives against any damages arising out of the use of any TI components in safety-critical applications.

In some cases, TI components may be promoted specifically to facilitate safety-related applications. With such components, TI's goal is to help enable customers to design and create their own end-product solutions that meet applicable functional safety standards and requirements. Nonetheless, such components are subject to these terms.

No TI components are authorized for use in FDA Class III (or similar life-critical medical equipment) unless authorized officers of the parties have executed a special agreement specifically governing such use.

Only those TI components which TI has specifically designated as military grade or "enhanced plastic" are designed and intended for use in military/aerospace applications or environments. Buyer acknowledges and agrees that any military or aerospace use of TI components which have *not* been so designated is solely at the Buyer's risk, and that Buyer is solely responsible for compliance with all legal and regulatory requirements in connection with such use.

TI has specifically designated certain components which meet ISO/TS16949 requirements, mainly for automotive use. Components which have not been so designated are neither designed nor intended for automotive use; and TI will not be responsible for any failure of such components to meet such requirements.

Products		Applications	
Audio	www.ti.com/audio	Automotive and Transportation	www.ti.com/automotive
Amplifiers	amplifier.ti.com	Communications and Telecom	www.ti.com/communications
Data Converters	dataconverter.ti.com	Computers and Peripherals	www.ti.com/computers
DLP® Products	www.dlp.com	Consumer Electronics	www.ti.com/consumer-apps
DSP	dsp.ti.com	Energy and Lighting	www.ti.com/energy
Clocks and Timers	www.ti.com/clocks	Industrial	www.ti.com/industrial
Interface	interface.ti.com	Medical	www.ti.com/medical
Logic	logic.ti.com	Security	www.ti.com/security
Power Mgmt	power.ti.com	Space, Avionics and Defense	www.ti.com/space-avionics-defense
Microcontrollers	microcontroller.ti.com	Video and Imaging	www.ti.com/video
RFID	www.ti-rfid.com		
OMAP Mobile Processors	www.ti.com/omap	TI E2E Community	e2e.ti.com
Wireless Connectivity	www.ti.com/wirelessconnectivity		

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 Copyright © 2012, Texas Instruments Incorporated